

BACK-END

IGBT

DIODE

THERMAL RESISTANCE TEST SYSTEM 過渡熱抵抗測定器

DVIPM60Z 600A

- DVIPM60Z is the test system with 600A forcing at maximum which is developed as the thermal resistance tester for IPM. This model can test 14 devices at maximum. In addition, it can manage device information by serial correspondence.
- IPM用の熱抵抗テスターとして開発された最大印加600Aのシステムで、最大14素子までの測定に対応しています。また、測定素子とシリアル通信にて、素子の情報を管理することができます。

MODEL	DVIPM60Z
MEASUREMENT RANGE	
V _{F1} /V _{F2} /V _P	0000mV~8191mV
ΔV _F	0000mV~1999mV
I _F	000.0A~600.0A
SETTING RANGE	
MEASURABLE DEVICES	DIODE, IGBT
I _F	000.0A~600.0A
I _M	1mA~999mA
POWER FORCING TIME(PT)	100μs~999ms
DELAY TIME(DT)	10μs~999μs
LOWER GATE(LG)/UPPER GATE(UG)	0000mV~1999mV
BINNING	
OPEN/SHORT CHECK	V _{F1} >4V...OPEN V _{F1} <0.2V...SHORT
BIN INDICATION	PASS, LOW, HIGH, TRIP, DATA-ERROR, REJECT
DIMENSIONS & WEIGHT	
MAIN UNIT	1100(W)×1060+395(D)×1700(H)...566kg



Forcing Power Range Diagram

